Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/730,191	SCHRAMM ET AL.
Examiner	Art Unit

2876

Seung H. Lee

SEARCHED					
Class	Subclass	Date	Examiner		
235	462.22- 462.24	12/27/2005	SHL		
235	462.41	12/27/2005	SHL		
235	462.43	12/27/2005	SHL		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
Same	As Above	12/27/2005	SHL		
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SEARCH NO (INCLUDING SEARCI)
	DATE	EXMR
235/454 (see printouts)	12/27/2005	SHL
PCT cites	12/27/2005	SHL